Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/710,730	CHEN ET AL.	
Examiner	Art Unit	
Evelyn A. Lester	2873	

	SEAR	CHED		
Class	Subclass	Da	ate	Examiner
359	891	12/2/	2005	EAL
-	707			
	722-724			
	737			
	738	7	F	-

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
Same As	Above	12/2/2005	EAL
	I		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST Search: USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB	12/2/2005	EAL